

P30270.A02



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Takashi TANAKA Group Art Unit : Not Yet Assigned
Appl. No. : 10/597,112 Examiner : Not Yet Assigned
 (National Stage of PCT/JP2005/000620)
Filed : July 12, 2006 Confirmation No. : 6348
For : SYSTEM AND METHOD FOR LOCATION RECOGNITION USING IC
TAGS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop AMENDMENT
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98,
Applicant hereby brings to the attention of the Examiner the following information.

The following documents were cited in an International Search Report with
respect to International Patent Application No. PCT/JP2005/000620, of which the
present application is the U.S. National Stage Application. Copies of the International
Search Report (in Japanese and English) have been filed concurrently with the present
application and should thus have already been brought to the attention of the Examiner.

- (1) Japanese Laid-Open Patent Application Publication No. 2003-158470,
together with an English language Abstract, and patent family member

U.S. Patent No. 5,952,922 to SHOBER, which issued on September 14, 1999; and

- (2) International Patent Application Publication No. WO 02/103645, along with patent family member U.S. Patent Application Publication No.

2003/0030568 to LASTINGER et al., which was published on February 13, 2003.

The relevance of these documents, as ascertained with respect to the international claims by the International Examiner, is set forth in the International Search Report.

Applicant further submit the following documents:

- (3) Japanese Laid-Open Patent Publication No. 2004-038621, together with an English language Abstract of the same, and patent family member U.S. Patent Application Publication No. 2006/0017544 to TANAKA et al., which was published on January 26, 2006. Applicant notes that the Japanese document is cited on page 6 of the specification of the above-captioned application.

Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. patent publications are not enclosed herewith. However, if any copy is needed, the Examiner is respectfully requested to contact the undersigned.


Applicant respectfully requests that the Examiner consider the above material and cite the same. Copies of the above-noted foreign and international documents, including the noted English language Abstracts, are attached hereto, and all of the

documents are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicant with the next official communication in the present application.

Applicant notes that an Office Action on the merits has not issued in the present application, and thus, no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,
Takashi TANAKA

 REG. No. 44,099
Bruce H. Bernstein
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September 28, 2006
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Atty. Docket No.
P30270

Application No.
10/597,112

INFORMATION DISCLOSURE STATEMENT

APPLICANT

(Use several sheets if necessary)

Applicant
Takashi TANAKA

Filing Date
July 12, 2006

Group
Unknown

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	2003	- 1 5 8 4 7 0	05/30/03	JAPAN			
	02	/ 1 0 3 6 4 5	12/27/02	W.I.P.O			
	2004	- 0 3 8 6 2 1	02/05/04	JAPAN			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	1	English language Abstract of JP 2003-158470.
	2	English language Abstract of JP 2004-038621.

EXAMINER

DATE CONSIDERED

***EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.